QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

APRIL 1985 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

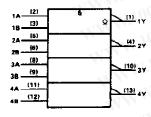
These devices contain four independent 2-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher VOH levels.

The SN5401 and SN54LS01 are characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to $125\,^{\circ}\text{C}$. The SN7401 and SN74LS01 are characterized for operation from $0\,^{\circ}\text{C}$ to $70\,^{\circ}\text{C}$.

FUNCTION TABLE (each gate)

INP	UTS	OUTPUT
A	В	Y C
Н	Had	N.M
j L	X	H
×	L	H

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

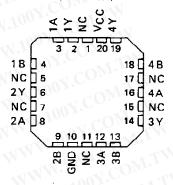
SN5401 ... J PACKAGE SN54LS01 ... J OR W PACKAGE SN7401 ... N PACKAGE SN74LS01 ... D OR N PACKAGE (TOP VIEW)

1Y		U14□ V.	o o
1A	\square 2	13 4	Ÿ
1B	□3	12 48	3
2Y	□₄	17 44	A
2A	□5	10 31	(1
2B	□ 6	9∏ 3∄	3
GND	□7	8 34	1

SN5401 . . . W PACKAGE (TOP VIEW)

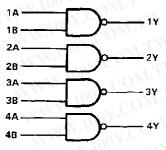
1A		U14] 4Y
1 B		13 AB
1Y		12 4A
Vcc		סאם ⊈יו
2Y	5	N 10 ∏ 3.B 1
2A	G 6	9 🗍 3A
2 B	\Box 7	8 □ 3 Υ

SN54LS01 . . . FK PACKAGE (TOP VIEW)



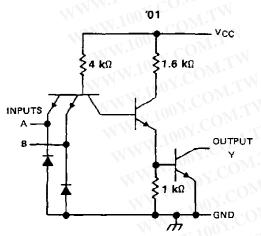
NC - No internal connection

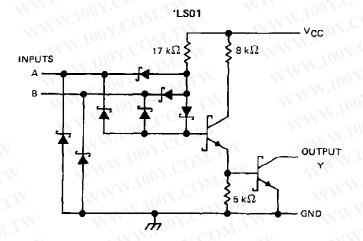
logic diagram (positive logic)



positive logic: $Y = \overline{A} \cdot \overline{B}$ or $Y = \overline{A} + \overline{B}$

schematics (each gate)





Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1): '01, 'LS01	
Input voltage: '01	
'LS01	7 V
Off-state output voltage	.O 7 V
Operating free-air temperature range: SN54'	
SN74′	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminals.

SN5401, SN7401 QUADRUPLE 2-INPUT POSITIVE NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	TO COM. THE WAY CONTROL	W	SN5401			SN7401			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
ViH	High-level input voltage	2		N	2	N 10	01.	V	
VIL	Low-level input voltage	TI	N	8.0	MM	_11	0.8	V	
۷он	High-level output voltage	COA	rW	5.5	WV	1111.	5.5	V	
IOL	Low-level output current	COM.	_ XX.	16	**	WW.	16	mA	
TA	Operating free-air temperature	- 55	. F. A.	125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5401	SN7401	UNIT
PARAIVIE ! ER	TEST CONDITIONS.	MIN TYP# MAX	MIN TYP [‡] MAX	UNIT
Vik	VCC = MIN, = -12 mA	- 1.5	-1.5	V
1	VCC = MIN, VIL = 0.8 V, VOH = 5.5 V	11001.	0.25	-3L1(
Іон	VCC = MIN, VIL = 0.7 V, VOH = 5.5 V	0.25	Win In	mA
v_{OL}	VCC = MIN, VIH = 2 V, IOL = 16 mA	0.2 0.4	0.2 0.4	٧
11	VCC = MAX, VI = 5.5 V	1	(1) (1)	mΑ
ПH	V _{CC} = MAX, V _I = 2.4 V	40	40	μΑ
կլ	V _{CC} = MAX, V _I = 0.4 V	-1.6	-1.6	mA
І ссн	$V_{CC} = MAX, V_{\parallel} = 0$	4 8	4 8	mA
^I CCL	$V_{CC} = MAX$, $V_{\parallel} = 4.5 \text{ V}$	12 22	12 22	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN TYP	MAX	UNIT
^T PLH	A or B	- TON W. 100	RL = 4 kΩ,	C _L = 15 pF	CON 35	55	ns
^t PHL	7010	W. 100	$R_L = 400 \Omega$,	C _L = 15 pF	(0)8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

SN54LS01, SN74LS01 QUADRUPLE 2-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

		COMP.	SN54LS01		SN74LS01			
	1700 100 100	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4,5	5	5.5	4.75	5	5.25	V
۷ін	High-level input voltage	OY.COM.T	W		2	- N 10	10 A.	V
VIL	Low-level input voltage	OUX.CO	M	0.7	WW	71	8.0	V
Voн	High-level output voltage	OV.COM	σW	5.5	W	MAA	5.5	V
OL	Low-level output current	100 ON	. F	4		WW	8	mΑ
T _A ≤	Operating free-air temperature	- 55	1.7.4	125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	W.IV		SN54LS01		SN74LS		
PARAMETER	W.100 Y	TEST CONDITIONS †	MIN TYP\$	MIN TYPE MAX MIN		MAX	UNIT
Vik	V _{CC} - MIN,	I _I = ~ 18 mA	Mar. COM	- 1.5		- 1.5	(V)
•он ≤	VCC = MIN,	VIL = MAX, VOH = 5.5 V	1001	0.1		0.1	mA
14	VCC = MIN,	VIH = 2 V, IOL = 4 mA	0.25	0.4	0.25	0.4	V
VOL	VCC = MIN,	V _{IH} = 2 V, I _{OL} = 8 mA	V. CC)IAT.	0.35	0.5	M.
ij	V _{CC} = MAX,	V _I = 7 V	W.IOO	0.1	-XN	0.1	mΑ
⁷ ГН	V _{CC} = MAX,	V _I = 2.7 V	W.100 1	20		20	μА
IIL	V _{CC} = MAX,	V ₁ = 0.4 V	100X	- 0.4	VII	- 0.4	mA
1ссн	VCC = MAX,	V _I = 0	0.8	1.6	0.8	1.6	mΑ
1CCL	V _{CC} = MAX,	V ₁ = 4.5 V	2.4	4.4	2.4	4.4	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, VCC = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN TYP	MAX	UNIT
^t PLH	A or B	M.M.	$R_1 = 2 k\Omega_s$	CL = 15 pF	17	32	ns
[‡] PHL	70.0	WWW.10	11L - 2 K32,	C[- 13 pr	C15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

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